

**Search Notes**

Application/Control No.

10/617,532

Examiner

Tianjie Chen

Applicant(s)/Patent under  
Reexamination

NAKAYAMA, MASATOSHI

Art Unit

2652

**SEARCHED**

Class	Subclass	Date	Examiner
360	122		
	126		
	234.5		
	235.2		
216	22	5/23/2005	TJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Esat Report	5/23/2005	TJ